



# Silicon Sensor Studies within the Scope of the Phase-2 Upgrade of the CMS Outer Tracker

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## **HL-LHC Upgrade in a Nutshell**







## **Phase-2 Outer Tracker Modules**



New module concept with 2 sensors on top of each other

#### 2 module types:



## **Phase-2 Outer Tracker Modules**



- New module concept with 2 sensors on top of each other
- 2 module types:
  - 2S (2 strip sensors)
  - PS (macro pixel + strip sensor)
- Sensor granularity decreases from center outwards



## The Phase-2 Outer Tracker Sensors





#### **2S**:

- A = 10 x 10 cm<sup>2</sup>
- Strips: 2 x 1016 = 2032
- Pitch: 90 µm

#### PS-s:

- A = 5 x 10 cm<sup>2</sup>
- Strips: 2 x 960 = 1920
- Pitch: 100 µm

#### PS-p:

- A = 5 x 10 cm<sup>2</sup>
- Macro pixel: 32 x 960 = 30208
- Pixel size: 100 x 1500 μm<sup>2</sup>













#### 1) Operation under reverse bias at full depletion

- $N_{\text{free charge carriers}} \approx O(10^8) >> S_{\text{particle}} \approx O(10^5)$ 
  - $\rightarrow$  full depletion is mandatory
- Leakage current I<sub>leak</sub> of sensor is a significant quantity



■ I<sub>leak</sub> ~ T

 $\rightarrow$  operation temperature in tracker T < 0





#### 2) Particle detection

- Traversing charged particles generate eh-pairs → eh-pairs are separated by E-filed → charge is collected by strips
- S<sub>particle</sub> is dependent on sensor thickness (~ 75 eh/µm)





#### 3) Signal

- Signal = most probable value (MPV) of signal distribution
- Sensor's MPV has to be well-above the noise of read-out electronics to make its operation efficient (rule of thumb: MPV/3 >  $4\sigma_{read-out}$ )





#### 4) Radiation damage

- Introduces defects in silicon lattice  $\rightarrow$  additional states within the band gap  $\rightarrow$  reduction of signal and increase of leakage current
- Expected maximum fluences after 10 years:





#### 5) Annealing

- Irradiated sensors anneal at room temperature (RT) → reduces leakage current and affects signal
- Annealing period during year-end technical stop possible



















#### **Material Studies at ETP – Recent Results**



Seed Signal vs. Annealing ( $\Phi$  = 3e14 n<sub>eq</sub> cm<sup>-2</sup>, V<sub>bias</sub> = 600 V, T = -20°C)



Comparison of 200, 240 and
300 µm material for

V<sub>bias</sub> = 600 V

- Signal of 200 µm material too low
- 240/300 µm provide similar signal and annealing characteristic at 600 V

## Material Studies at ETP – Irradiation Studies



- ETP is leading institute in terms of irradiation studies due to powerful self-built setups and infrastructure
- Material decision will be made almost exclusively based on our studies
- More than 10 years of
  - Irradiation studies
  - Sensor qualification
  - Vendor qualification
- Final irradiation campaign on-going (material decision this summer)



## **Back Up**











